

| | Search Text | DBs |
|----|---|---|
| 1 | flip near5 chip | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB |
| 2 | S11 and (attach\$3 same chip same device) | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB |
| 3 | S12 and (inject\$3 same mold\$3) | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB |
| 4 | S13 and (hole or aperture or via or opening) | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB |
| 5 | S13 and ((hole or aperture or via or opening) same mold\$3) | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB |
| 6 | S13 and ((hole or aperture or via or opening) same mold\$3) and encapsulat\$3 | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB |
| 7 | (264/272.11,272.17,328.1).CCLS. | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB |
| 8 | S18 and ((inject\$3 same mold\$3) same encapsulat\$3) and pin | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB |
| 9 | (264/272.17).CCLS. | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB |
| 10 | S11 and (direct near5 chip near5 attach\$3 same device) | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB |
| 11 | S18 and (direct near5 chip near5 attach\$3 same device) | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB |
| 12 | (264/271.1,272.11,272.17,273,279.1).CCLS. | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB |
| 13 | (438/112,124,127).CCLS. | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB |
| 14 | (438/108,118,122,123).CCLS. | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB |
| 15 | S29 and S33 | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB |
| 16 | S35 and ((hole or opening) same bump) | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB |

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| 17 | (264/271.1,272.11,272.17,273,279.1).CCLS. | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB |
| 18 | (438/112,124,127).CCLS. | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB |
| 19 | S38 and S39 | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB |
| 20 | S40 and MOSFET | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB |
| 21 | (264/272.17).CCLS. | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB |
| 22 | S45 and (flip same bump) | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB |
| 23 | ((264/272.17) or (438/127)).CCLS. | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB |
| 24 | S48 and MOSFET | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB |
| 25 | S48 and (flag and MOSFET and (frame or support)) | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB |
| 26 | S48 and encapsulat\$3 and bump | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB |
| 27 | S48 and encapsulat\$3 and bump and ((cut\$3 or remov\$3) same resin) | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB |
| 28 | S48 and encapsulat\$3 and bump and ((cut\$3 or remov\$3) same resin) and flip | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB |
| 29 | S48 and (bump near5 gold) | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB |
| 30 | S48 and mosfet and (bump near5 gold) | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB |
| 31 | ((264/271.1,272.11,272.17,273,279.1) or (438/112,124,127)).CCLS. | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB |
| 32 | S61 and mosfet and (bump near5 gold) | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB |

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| 33 | S61 and (bump near5 gold) | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB |
| 34 | S61 and (bump near5 gold) and flag | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB |
| 35 | injection same mold\$3 same pin same (hole or opening) | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB |
| 36 | injection same mold\$3 same pin same (hole or opening) same reduc\$3 same flash | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB |
| 37 | ("20040178537").PN. | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB |
| 38 | injection same mold\$3 same pin same (opening) same reduc\$3 same flash | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB |
| 39 | injection same mold\$3 same pin same (opening) | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB |
| 40 | injection same mold\$3 same pin same inside same mold same (opening) | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB |